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| Examiner's Initials# | Cite No | Include name of the author (in CAPITAL LETTERS) title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, relevant page(s), volume-issue number(s), publisher, city and/or country where published.     | Translation (Y/N) |
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| EXAMINER <i>aw</i> | DATE CONSIDERED 10/30/02 |
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